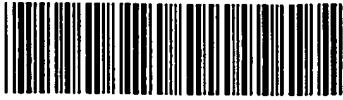


Search Notes 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/750,580	HIGASHI ET AL.	
				Examiner	Art Unit	
				Thinh T. Nguyen	2818	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
257	777	12/5/2005	TTN	EAST	12/5/2005	TTN
257	437	12/5/2005	TTN	EAST	12/6/2005	TTN
257	433	12/6/2005	TTN	EAST	4/9/07	TTN
257	739	12/6/2005	TTN			
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			